Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/765,954	HWANG ET AL.	
Examiner	Art Unit	
TAN X. DINH	2627	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST (see search history printout)	8/16/2007	T.D	
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